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Abstract:The 2012 IEEE Radio Frequency Integrated Circuits (RFIC) Symposium, to be held in Montreal, Canada, on June 17-19, 2012, will focus on the technical accomplishments in RF devices, circuits, and systems. Attendees can participate in 13 RFIC workshops and one joint RFICIMS workshop for 2012, which will cover broad ranges of RF topics including mm-wave silicon PAs, fast-settling RF frequency synthesis, wireline transceivers, and RF at the nanoscale. The conference will hold a plenary session of Prof. Thomas Lee of Stanford University on the subject 'The Last Frontier: Terahertz Electronics'. Robert Gilmore, vice president of engineering at Qualcomm, will talk on 'Towards the 5G Smartphone: Greater System Capacity, More Bands, Faster Data Rates, Advanced Applications, and Longer Battery Life'.

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Main heading:Digital integrated circuits

Controlled terms: Microwave integrated circuits - Radiation

Uncontrolled terms: Advanced applications - Battery life - Data rates - mm-Wave - Nano scale - Plenary sessions - Qualcomm - Radio frequency integrated circuits - RF devices - RF frequencies - Stanford University - System Capacity - Terahertz electronics - Vice president

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